

MB8299-25/-35

CMOS 288K-BIT HIGH-SPEED BiCMOS SRAM

32K Words x 9 Bits BiCMOS High-Speed Static Random Access Memory

The Fujitsu MB8299 is a high-speed static random access memory organized as 32,768 words x 9 bits and fabricated with CMOS technology. To obtain a smaller chip size, the cells use NMOS transistors and resistors. The MB8299 is housed in 300 mil plastic DIP and SOJ packages, and a 450 mil SOP package. All pins are TTL compatible and a single +5 V power supply is required.

A separate chip select (CS_1) pin simplifies multipackage systems design by permitting the selection of an individual package when outputs are OR-tied, and then automatically powering down the other deselected packages.

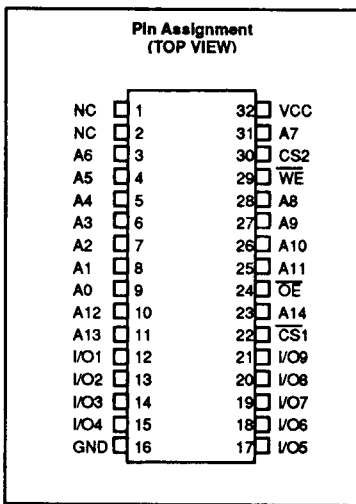
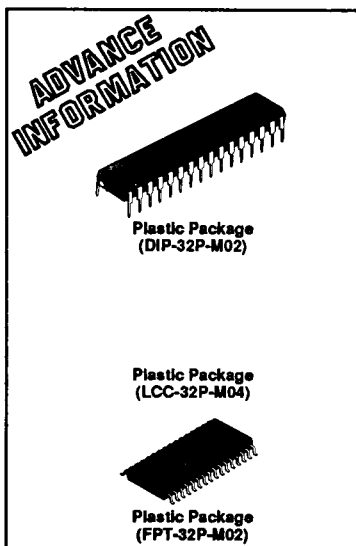
The MB8299 offers low power dissipation, low cost, and high performance.

- Organization: 32,768 words x 9 bits
- Static operation: no clocks or timing strobe required
- Access time: $t_{AA} = t_{ACS} = 25$ ns max. (MB8299-25)
 $t_{AA} = t_{ACS} = 35$ ns max. (MB8299-35)
- Low power consumption: 715 mW max. (Operating) for 25 ns
605 mW max. (Operating) for 35 ns
138 mW max. (TTL Standby)
27.5 mW max. (CMOS Standby)
- Single +5 V power supply $\pm 10\%$ tolerance
- TTL compatible inputs and outputs
- Three-state outputs with OR-tie capability
- Electrostatic protection for all inputs and outputs
- Standard 32-pin Plastic Packages:
Skinny DIP (300 mil) MB8299-xxPSK
SOJ (300 mil) MB8299-xxPJ
SOP (450 mil) MB8299-xxPF

Absolute Maximum Ratings (See Note)

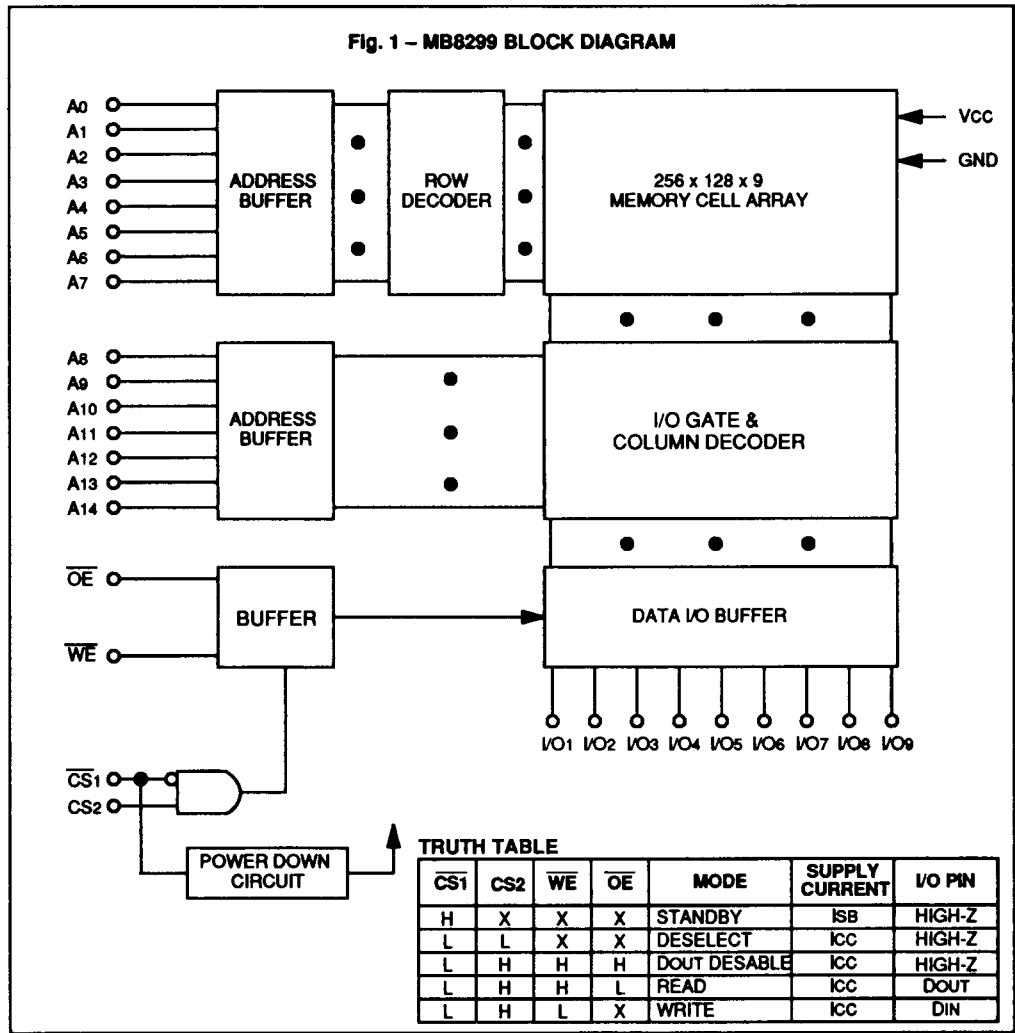
Rating	Symbol	Value	Unit
Supply Voltage	V_{CC}	-0.5 to +7	V
Input Voltage on any pin with respect to GND	V_{IN}	-3.5 to +7	V
Output Voltage on any I/O pin with respect to GND	V_{OUT}	-0.5 to +7	V
Output Current	I_{OUT}	± 20	mA
Power Dissipation	P_D	1.0	W
Temperature Under Bias	T_{BIAS}	-10 to +85	$^{\circ}C$
Storage Temperature Range	T_{STG}	-45 to +125	$^{\circ}C$

Note: Permanent device damage may occur if absolute maximum ratings are exceeded. Functional operation should be restricted to the conditions as detailed in the operation sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields. However, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltage to this high impedance circuit.

Fig. 1 – MB8299 BLOCK DIAGRAM



CAPACITANCE (T_A = 25° C, f = 1MHz)

Parameter	Condition	Symbol	Min	Typ	Max	Unit
Input Capacitance ($\overline{\text{CS1}}$, CS2 $\overline{\text{OE}}$, $\overline{\text{WE}}$)	V _{IN} = 0V	C _{I1}			8	pF
Input Capacitance (Other Input)	V _{IN} = 0V	C _{I2}			7	pF
I/O Capacitance	V _{I/O} = 0V	C _{I/O}			8	pF

RECOMMENDED OPERATING CONDITIONS

(Referenced to GND)

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	VCC	4.5	5.0	5.5	V
Ambient Temperature	TA	0		70	°C

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DC CHARACTERISTICS

(Recommended operating conditions unless otherwise noted.)

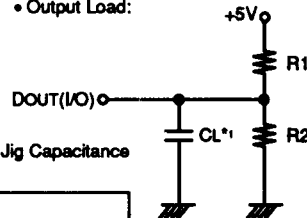
Parameter	Symbol	Test Condition	Min	Max	Unit
Standby Supply Current	ISB1	$\overline{CS1} \geq VCC - 0.2V$ $VIN \geq VCC - 0.2V$ or $VIN \leq 0.2V$		5	mA
	ISB2	$VIN \leq 0.2V$ $\overline{CS1} = VIH$		25	mA
Operating Supply Current	ICC	$IOUT = 0mA$, $\overline{CS1} = VIL$ Cycle = Min.		130	mA
				110	
Input Leakage Current	ILI	$VIN = 0V$ to VCC , $VCC = Max.$	-5	5	μA
Output Leakage Current	ILVO	$\overline{CS1} = VIH$ or $\overline{CS2} = VIL$ or $WE = VIL$ or $OE = VIH$, $VIO = 0V$ to VCC	-5	5	μA
Input Low Voltage	VIL		-2.0*	0.8	V
Input High Voltage	VIH		2.2	6.0	V
Output High Voltage	VOH	$I OH = -4mA$	2.4		V
Output Low Voltage	VOL	$I OL = 8mA$		0.4	V

Note: *1 -2.0V Min. for pulse width less than 20% of cycle time. (VIL min. = -0.5V at DC level)

Fig. 2 – AC TEST CONDITIONS

- Input Pulse Levels: 0V to 3.0V
- Input Pulse Rise & Fall Times: 3ns (Transient between 0.8V and 2.2V)
- Timing Reference Levels: Input : $VIL = 0.8V$, $VIH = 2.2V$
Output : $VOL = 0.8V$, $VOH = 2.2V$

• Output Load:



*1 Including Scope and Jig Capacitance

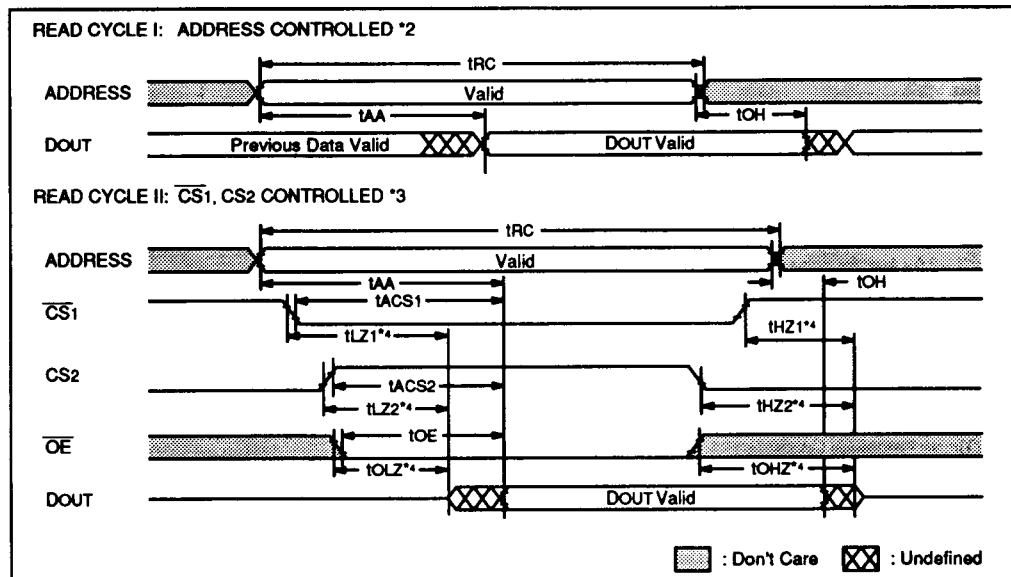
	R1	R2	CL	Parameters Measured
Load I	480k Ω	255 Ω	30pF	except tLZ1, tLZ2, tHZ1, tHZ2, tWZ, tOW, tOLZ and tOHZ
Load II	480k Ω	255 Ω	5pF	tLZ1, tLZ2, tHZ1, tHZ2, tWZ, tOW, tOLZ and tOHZ

AC CHARACTERISTICS

(Recommended operating conditions unless otherwise noted.)

Parameter	Symbol	MB8299-25		MB8299-35		Unit
		Min	Max	Min	Max	
Read Cycle Time	t _{RC}	25		35		ns
Address Access Time *2	t _{AA}		25		35	ns
CS1 Access Time *3	t _{ACS1}		25		35	ns
CS2 Access Time *3	t _{ACS2}		14		15	ns
OE Access Time	t _{OE}		12		14	ns
Output Hold from Address Change	t _{OH}	3		3		ns
Output Low-Z from $\overline{CS1}$ *4	t _{LZ1}	5		8		ns
Output Low-Z from CS2 *4	t _{LZ2}	2		3		ns
Output Low-Z from $\overline{OE}$ *4	t _{OLZ}	2		3		ns
Output High-Z from $\overline{CS1}$ *4	t _{HZ1}	1	15	1	15	ns
Output High-Z from CS2 *4	t _{HZ2}	1	15	1	15	ns
Output High-Z from $\overline{OE}$ *4	t _{OHZ}	1	15	1	15	ns

READ CYCLE TIMING DIAGRAM *1



- Note:
- *1 $\overline{WE}$ is high for Read Cycle.
 - *2 Device is continuously selected, $\overline{CS1} = \text{VIL}$, $\text{CS2} = \text{VIH}$ and $\overline{OE} = \text{VIL}$.
 - *3 Address valid prior to or coincident with $\overline{CS1}$ transition low, CS2 transition high.
 - *4 Transition is specified at the point of $\pm 500\text{mV}$ from steady state voltage with specified Load II in Fig. 2.

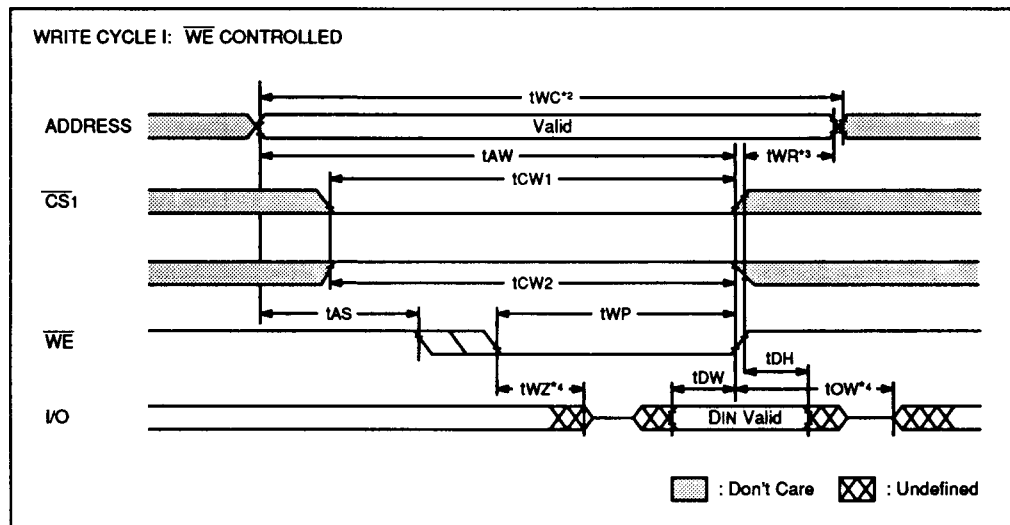
AC CHARACTERISTICS

(Recommended operating conditions unless otherwise noted)

WRITE CYCLE*1

Parameter	Symbol	MB8299-25		MB8299-35		Unit
		Min	Max	Min	Max	
Write Cycle Time*2	tWC	25		35		ns
Address Valid to End of Write	tAW	18		28		ns
CS1 to End of Write	tCW1	16		26		ns
CS2 to End of Write	tCW2	13		20		ns
Data Setup Time	tDW	8		12		ns
Data Hold Time	tDH	0		0		ns
Write Pulse Width	tWP	15		20		ns
Write Recovery Time*3	tWR	0		0		ns
Address Setup Time	tAS	0		0		ns
Output Low-Z from $\overline{WE}$ *4	tOW	0		0		ns
Output High-Z from $\overline{WE}$ *4	tWZ	0	8	0	14	ns

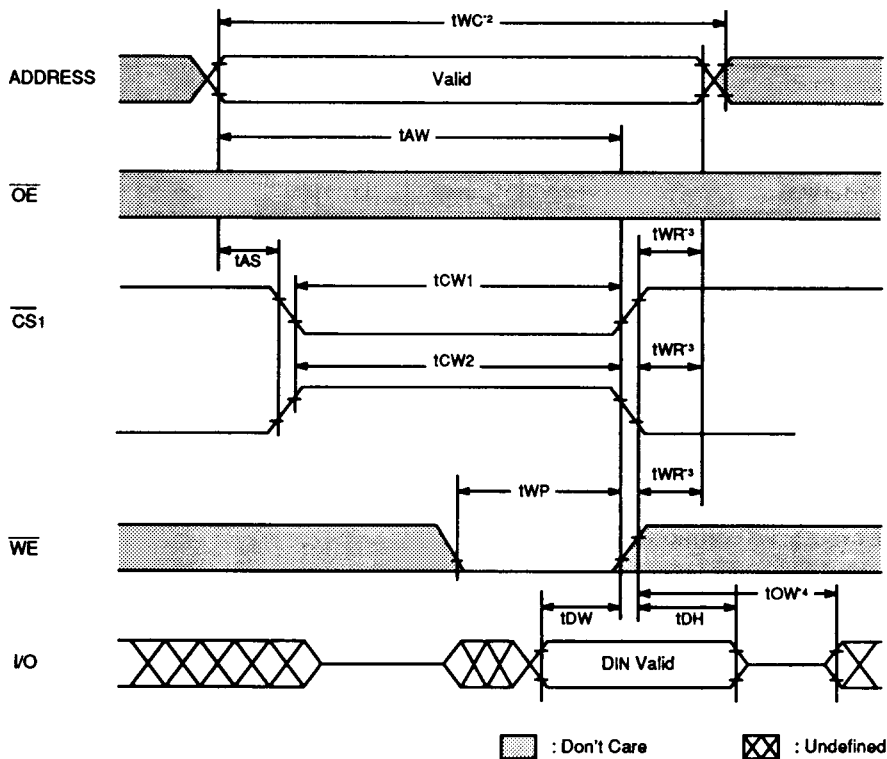
WRITE CYCLE TIMING DIAGRAM *1



- Note:**
- *1 If $\overline{CS}$ goes high simultaneously with $\overline{WE}$ high, the output remains in high impedance state.
 - *2 All Write Cycles are determined from the last address transition to the first address transition of next address.
 - *3 tWR is defined from the end point of Write Mode.
 - *4 Transition is specified at the point of $\pm 500\text{mV}$ from steady state voltage with specified Load II in Fig. 2.

WRITE CYCLE TIMING DIAGRAM¹

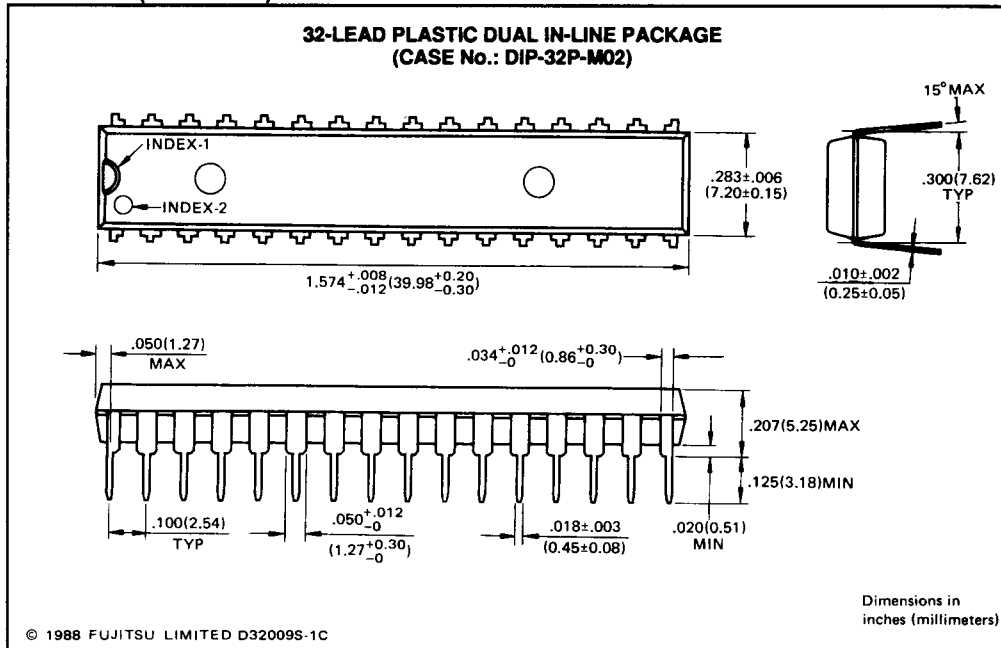
WRITE CYCLE No. II: $\overline{CS1}$, $CS2$ CONTROLLED



- Note:**
- *1 If $\overline{CS}$ goes high simultaneously with $\overline{WE}$ high, the output remains in high impedance state.
 - *2 All Write Cycles are determined from the last address transition to the first address transition of next address.
 - *3 t_{WR} is defined from the end point of Write Mode.
 - *4 Transition is specified at the point of $\pm 500\text{mV}$ from steady state voltage with specified Load II in Fig. 2.

PACKAGE DIMENSIONS

PLASTIC DIP (Suffix: P-SK)

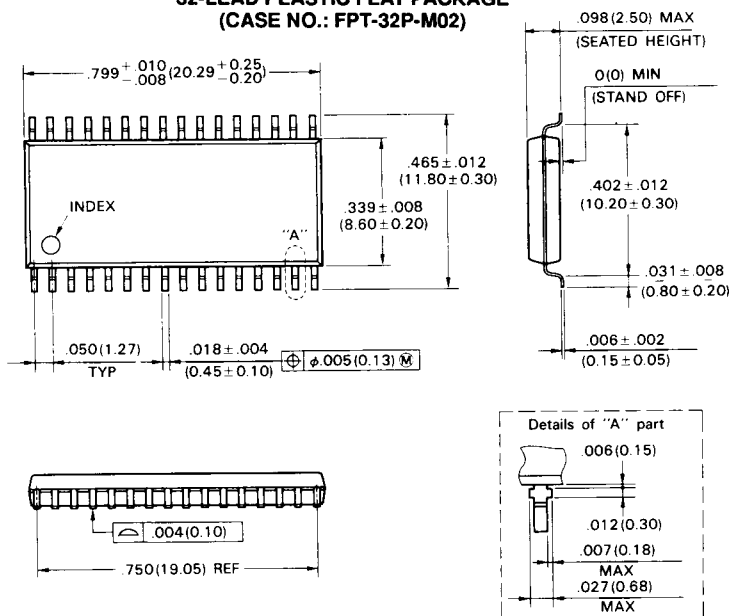


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PACKAGE DIMENSIONS (Continued)

Plastic FPT (Suffix: PF)

32-LEAD PLASTIC FLAT PACKAGE (CASE NO.: FPT-32P-M02)



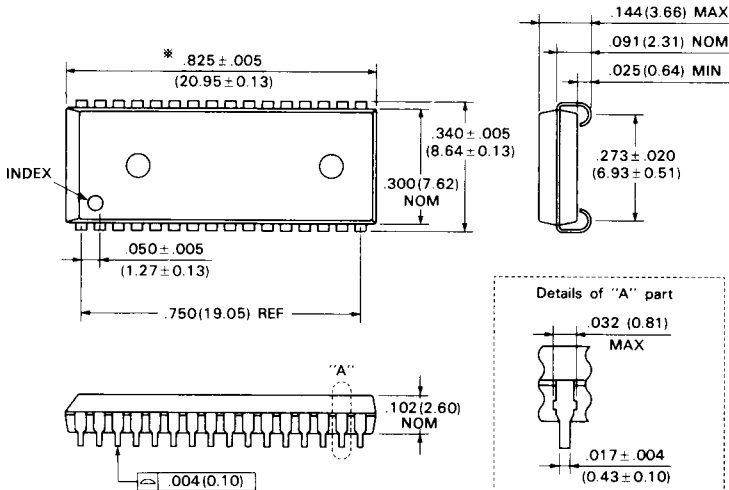
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Dimensions in
inches (millimeters)

PACKAGE DIMENSIONS (Continued)

PLASTIC FPT (Suffix: PJ)

32-LEAD PLASTIC LEADED CHIP CARRIER (CASE No.: LCC-32P-M04)



* : This dimension includes resin protrusion. (Each side : .006 (0.15) MAX)

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Dimensions in
inches (millimeters)